TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74HC4049AP, TC74HC4049AF, TC74HC4049AFN, TC74HC4049AFT TC74HC4050AP, TC74HC4050AF, TC74HC4050AFN, TC74HC4050AFT

TC74HC4049AP/AF/AFN/AFT HEX BUFFER / CONVERTER (INVERTING)
TC74HC4050AP/AF/AFN/AFT HEX BUFFER / CONVERTER

The TC74HC4049A and TC74HC4050A are high speed CMOS HEX BUFFERs fabricated with silicon gate C2MOS technology.

They achieve the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

The TC74HC4049A is an inverting buffer, while the TC74HC4050A is a non-inverting buffer. The internal circuits are composed of 3-stages (HC4049A) or 2-stages (HC4050A) of invertaers, which provided high noise immunity and stable output.

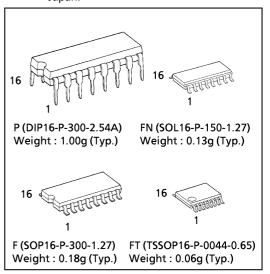
Input protection circuits are different from those of other high speed CMOS IC's. They eliminate the diodes on the  $V_{\rm CC}$  side thus providing of logic - level conversion from high - level volages up to 15V to low - level voltages.

They are useful for battery back up circuits, because input voltage can be applied on IC's which are not biased by  $V_{\rm CC}$ .

#### FEATURES:

- High Speed······· $t_{pd}$  = 9ns(typ.) at  $V_{CC}$  = 5V
- Low Power Dissipation ................ $I_{CC} = 1 \mu A(Max.)$  at  $Ta = 25 ^{\circ}C$
- High Noise Immunity  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (Min.)
- Output Drive Capability ---------15 LSTTL Loads
- Symmetrical Output Impedance… | I<sub>OH</sub> | = I<sub>OL</sub> = 6mA (Min.)
- Balanced Propagation Delays ····· t<sub>pLH</sub> ≃ t<sub>pHL</sub>
- Wide Operating Voltage Range ···· V<sub>CC</sub> (opr.) = 2V~6V
- Pin and Function Compatible with 4049B/4050B

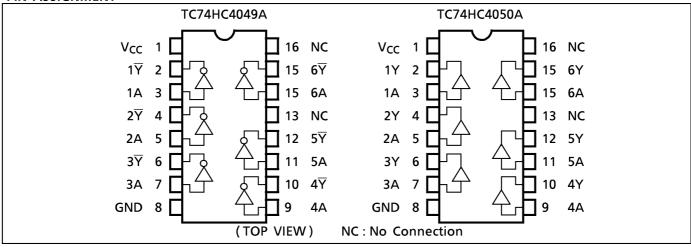
(Note) The JEDEC SOP (FN) is not available in Japan.



#### TRUTH TABLE

₹(4049A)	Y(4050A)
Н	L
L	Н
	▼ ( 4049A )         H         L

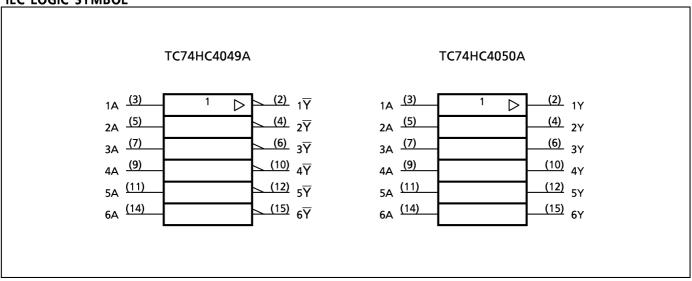
#### **PIN ASSIGNMENT**



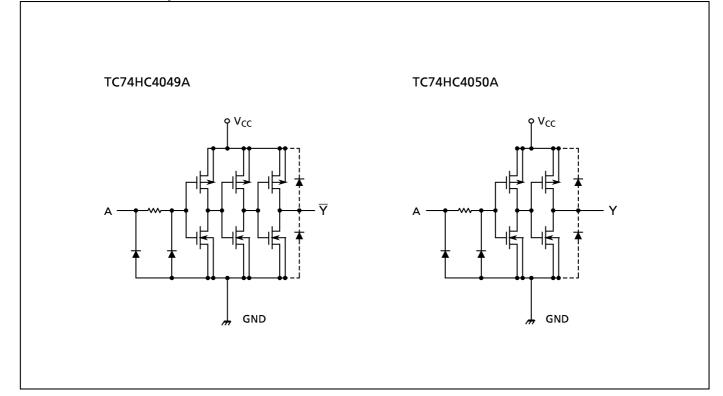
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## **IEC LOGIC SYMBOL**



## INPUT and OUTPUT EQUIVALENT CIRCUIT



#### **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	$V_{cc}$	<b>−</b> 0.5~7	V
DC Input Voltage	V <sub>IN</sub>	<b>−0.5~18*</b>	V
DC Output Voltage	V <sub>OUT</sub>	$-0.5 \sim V_{CC} + 0.5$	V
Input Diode Current	I <sub>IK</sub>	<b>-20</b>	mΑ
Output Diode Current	I <sub>OK</sub>	± 20	mA
DC Output Current	I <sub>OUT</sub>	± 35	mA
DC V <sub>CC</sub> / Ground Current	I <sub>cc</sub>	± 75	mΑ
Power Dissipation	<b>P</b> <sub>D</sub>	500(DIP)**/180 (SOP,TSSOP)	mW
Storage Temperature	T <sub>stg</sub>	<b>−65~150</b>	°C

- Note) \* DC input voltage ( $V_{\rm IN}$ ) specified is measured to GND and is not related to  $V_{\rm CC}$ . Recommended operating range is 0V to 15V and it is possible to convert logic-levels from 15V to 5V or 5V to 2V.
  - \*\* 500 mW in the range of  $Ta = -40 ^{\circ}\text{C} \sim 65 ^{\circ}\text{C}$ . From  $Ta = 65 ^{\circ}\text{C}$  to  $85 ^{\circ}\text{C}$  a derating factor of  $-10 \text{mW}/^{\circ}\text{C}$  shall be applied until 300 mW.

### **RECOMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V <sub>cc</sub>	2~6	>
Input Voltage	V <sub>IN</sub>	0~15	<b>V</b>
Output Voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	٧
Operating Temperature	T <sub>opr</sub>	<b>−40~85</b>	°C
Input Rise and Fall Time	t <sub>r</sub> , t <sub>f</sub>	$0 \sim 1000 (V_{CC} = 2.0V)$ $0 \sim 500 (V_{CC} = 4.5V)$ $0 \sim 400 (V_{CC} = 6.0V)$	ns

#### DC FLECTRICAL CHARACTERISTICS

DC ELECTRICAL CHARACTERISTICS										
PARAMETER SYM	SYMBOL	TEST CONDITION		V <sub>cc</sub>	Ta = 25°C			Ta = -40~85°C		UNIT
FARAIVIETER STIVIBO		TEST CONDITION			MIN.	TYP.	MAX.	MIN.	MAX.	OIVII
High - Level Input Voltage	V <sub>IH</sub>				1.50 3.15 4.20			1.50 3.15 4.20		٧
Low - Level Input Voltage	VIL				_ 	111	0.50 1.35 1.80	_ _ _	0.50 1.35 1.80	٧
High - Level Output Voltage	$V_{OH}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -20\mu A$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0		1.9 4.4 5.9		v	
		V <sub>IH</sub> or V <sub>IL</sub>	$I_{OH} = -6 \text{ mA}$ $I_{OH} = -7.8 \text{ mA}$	4.5 6.0	4.18 5.68	4.31 5.80	_	4.13 5.63	_	
Low - Level Output Voltage	V <sub>OL</sub>	V <sub>IN</sub> =	$I_{OL} = 20 \mu A$	2.0 4.5 6.0	111	0.0 0.0 0.0	0.1 0.1 0.1	_ _ _	0.1 0.1 0.1	\ \
	$V_{\text{IH}}$ or $V_{\text{IL}}$	$I_{OL} = 6$ mA $I_{OL} = 7.8$ mA	4.5 6.0		0.17 0.18	0.26 0.26	=	0.33 0.33		
Input Leakage Current $I_{1N}$ $V_{1N} = V_{CC}$ or $V_{1N} = 15V$	c or GND	6.0	_	_	± 0.1	_	± 1.0			
	ויי	V <sub>I N</sub> = 15V		6.0	_	_	± 0.5	_	± 5.0	_ μ <b>Α</b> [
Quiescent Supply Current	I <sub>cc</sub>	$V_{IN} = V_{CC}$ or GND			_	_	1.0	_	10.0	

## AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 6ns$ )

PARAMETER	CVMBOL	TEST CONDITION	CL (pF)	V <sub>CC</sub>	Ta = 25°C			Ta = -40~85°C		UNIT
FARAIVIETER	SYMBOL			(v) [	MIN.	TYP.	MAX.	MIN.	MAX.	וואוטן
	t <sub>TLH</sub>			2.0	_	25	60	_	75	
Output Transition Time	t <sub>THL</sub>		50	4.5	-	6	12	_	15	l I
	THL			6.0	_	5	10	_	13	
Propagation Delay Time				2.0	_	30	75	_	95	
	t <sub>pLH</sub> t <sub>pHL</sub>		50	4.5	-	9	15	–	19	ns
				6.0	_	8	13	_	16	
			150	2.0	_	45	100	_	145	
				4.5	–	14	20	–	29	
				6.0	_	12	17	_	25	
Input Capacitance	C <sub>IN</sub>				_	5	10	_	10	n=
Power Dissipation Capacitance	C <sub>PD</sub> (1)				_	26	_	_	_	pF

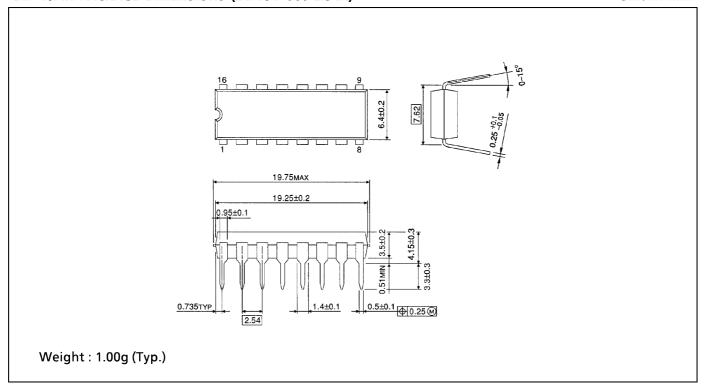
Note (1) C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC}$  (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 6$  (per Gate)

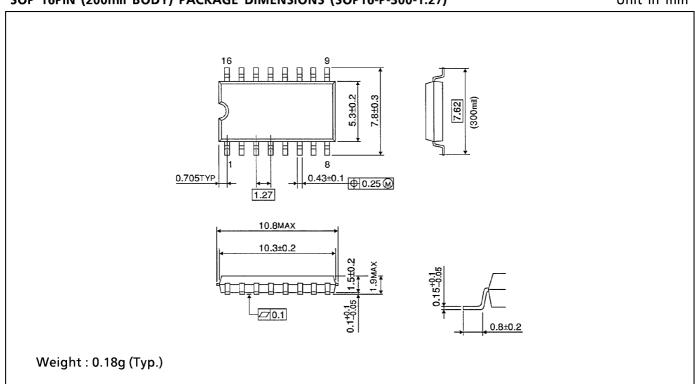
## DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)

Unit in mm



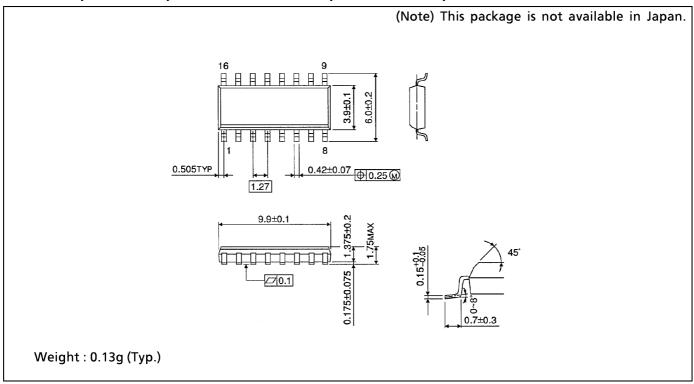
## SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)

Unit in mm



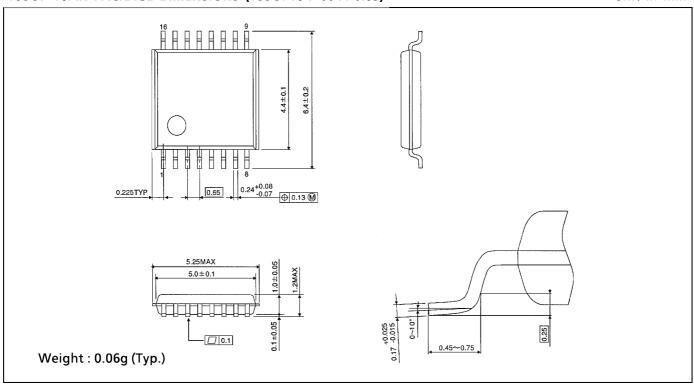
## SOP 16PIN (150mil BODY) PACKAGE DIMENSIONS (SOL16-P-150 -1.27)

Unit in mm



## TSSOP 16PIN PACKAGE DIMENSIONS (TSSOP16-P-0044-0.65)

Unit in mm



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